

# SI2351DS

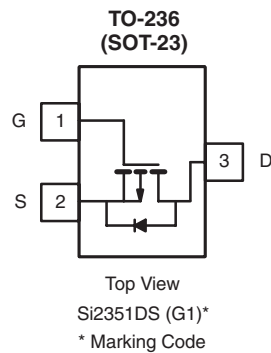
MOSFET PRODUCT SUMMARY			
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)
- 20	0.115 at V <sub>GS</sub> = - 4.5 V	- 3.0	3.2 nC
	0.205 at V <sub>GS</sub> = - 2.5 V	- 2.2	

## FEATURES

- Halogen-free Option Available
- TrenchFET<sup>®</sup> Power MOSFET
- PWM Optimized
- 100 % R<sub>g</sub> Tested



**RoHS**  
COMPLIANT



Ordering Information: Si2351DS-T1-E3 (Lead (Pb)-free)  
Si2351DS-T1-GE3 (Lead (Pb)-free and Halogen-free)

ABSOLUTE MAXIMUM RATINGS T <sub>A</sub> = 25 °C, unless otherwise noted			
Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	- 20	V
Gate-Source Voltage	V <sub>GS</sub>	± 12	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	I <sub>D</sub>	T <sub>C</sub> = 25 °C	- 2.8
		T <sub>C</sub> = 70 °C	- 2.4
		T <sub>A</sub> = 25 °C	- 2.2 <sup>b, c</sup>
		T <sub>A</sub> = 70 °C	- 1.8 <sup>b, c</sup>
Pulsed Drain Current	I <sub>DM</sub>	- 10	A
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C	
		T <sub>A</sub> = 25 °C	- 0.9 <sup>1b, c</sup>
Maximum Power Dissipation	P <sub>D</sub>	T <sub>C</sub> = 25 °C	2.1
		T <sub>C</sub> = 70 °C	1.5
		T <sub>A</sub> = 25 °C	1.0 <sup>b, c</sup>
		T <sub>A</sub> = 70 °C	0.7 <sup>b, c</sup>
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b, d</sup>	R <sub>thJA</sub>	90	115	°C/W
Maximum Junction-to-Foot (Drain)	R <sub>thJF</sub>	60	75	

Notes:

- Based on T<sub>C</sub> = 25 °C.
- Surface Mounted on 1" x 1" FR4 board.
- t = 5 s.
- Maximum under Steady State conditions is 130 °C/W.



# SI2351DS

<b>MOSFET SPECIFICATIONS</b> $T_J = 25\text{ }^\circ\text{C}$ , unless otherwise noted						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{DS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$	-20			V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250\text{ }\mu\text{A}$		-16.7		mV/°C
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		2.1			
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$	-0.6		-1.5	V
Gate-Source Leakage	$I_{GSS}$	$V_{DS} = 0\text{ V}, V_{GS} = \pm 12\text{ V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -20\text{ V}, V_{GS} = 0\text{ V}$			-1	$\mu\text{A}$
		$V_{DS} = -20\text{ V}, V_{GS} = 0\text{ V}, T_J = 55\text{ }^\circ\text{C}$			-10	
On-State Drain Current <sup>a</sup>	$I_{D(on)}$	$V_{DS} \geq -5\text{ V}, V_{GS} = -4.5\text{ V}$	-10			A
Drain-Source On-State Resistance <sup>a</sup>	$R_{DS(on)}$	$V_{GS} = -4.5\text{ V}, I_D = -2.4\text{ A}$		0.092	0.115	$\Omega$
		$V_{GS} = -2.5\text{ V}, I_D = -1.8\text{ A}$		0.164	0.205	
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = -10\text{ V}, I_D = -2.4\text{ A}$		5.5		S
<b>Dynamic<sup>b</sup></b>						
Input Capacitance	$C_{iss}$	$V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$		250		$\mu\text{F}$
Output Capacitance	$C_{oss}$		80			
Reverse Transfer Capacitance	$C_{rss}$		55			
Total Gate Charge	$Q_g$	$V_{DS} = -10\text{ V}, V_{GS} = -5.0\text{ V}, I_D = -2.4\text{ A}$		3.4	5.1	nC
		$V_{DS} = -10\text{ V}, V_{GS} = -4.5\text{ V}, I_D = -2.4\text{ A}$		3.2	5	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = -10\text{ V}, V_{GS} = -4.5\text{ V}, I_D = -2.4\text{ A}$		0.5		
Gate-Drain Charge	$Q_{gd}$		1.4			
Gate Resistance	$R_g$	$f = 1\text{ MHz}$		8.5	13	$\Omega$
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -10\text{ V}, R_L = 5.26\text{ }\Omega$ $I_D \cong -1.9\text{ A}, V_{GEN} = -4.5\text{ V}, R_G = 1\text{ }\Omega$		9	14	ns
Rise Time	$t_r$		30	45		
Turn-Off Delay Time	$t_{d(off)}$		32	48		
Fall Time	$t_f$		16	24		
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Source-Drain Diode Current	$I_S$	$T_C = 25\text{ }^\circ\text{C}$			-2.0	A
Pulse Diode Forward Current <sup>a</sup>	$I_{SM}$				-10	
Body Diode Voltage	$V_{SD}$	$I_S = -2.0\text{ A}$		-0.8	-1.2	V
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F = -2.0\text{ A}, di/dt = 100\text{ A}/\mu\text{s}, T_J = 25\text{ }^\circ\text{C}$		17	26	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$		5	8	nC	
Reverse Recovery Fall Time	$t_a$		14		ns	
Reverse Recovery Rise Time	$t_b$		3			

Notes:

- a. Pulse test; pulse width  $\leq 300\text{ }\mu\text{s}$ , duty cycle  $\leq 2\%$ .
- b. Guaranteed by design, not subject to production testing.